



*Industrial Computing Platform Partner*

# **AIS-Q450**

**With 3.5" SATA HDD**

## **Environment Test Report**

**Report NO: 09I020024**

Issued by: **Rex-Chang** / **08/10/2009**  
\_\_\_\_\_  
Test Engineer Date

Reviewed by: **Wenyuan Yang** / **08/10/2009**  
\_\_\_\_\_  
Manager Date

# Test item list

1. <i>Test item list</i> -----	2
2. <i>Temperature rise test</i> -----	3
3. <i>Temperature cycle operation test</i> -----	6
4. <i>High temperature storage test</i> -----	7
5. <i>Low temperature storage test</i> -----	8
6. <i>Humidity test</i> -----	9
7. <i>Cold start and hot start test</i> -----	10

## Test Configuration:

Num	Item	Spec
1.	Control Box:	AIS-Q450
	1. Main Board	AAEON IMBI-Q45 Rev. A0.1 (BIOS Ver: 1.0)
	2. CPU	Intel Core 2 Quad Q9400 / 2.66GHz
	3. Memory	Transcend 2GB * 2 / SEC K4B1G0846GD / DDR3
	5. SATA HDD	Seagate ST3160813AS / 160GB
	6. ATX Power Supply	CWT PSM220H / 220W

# Temperature rise test

**Test Date:** 08-05-2009

**Test Product:** AIS-Q450

**Test Site:** AAEON QA Internal Lab.

**Test Standard:** Reference EN 61131-2(94), UL508 (94)

**Temperature Measurement:**

40 Channel Thermal Recorder:  
YOKOGAWA Inc,  
Model: DA100-13-1D  
Date of Calibration: 12/08/09  
Serial Number: 12A323190

**Test Condition:**

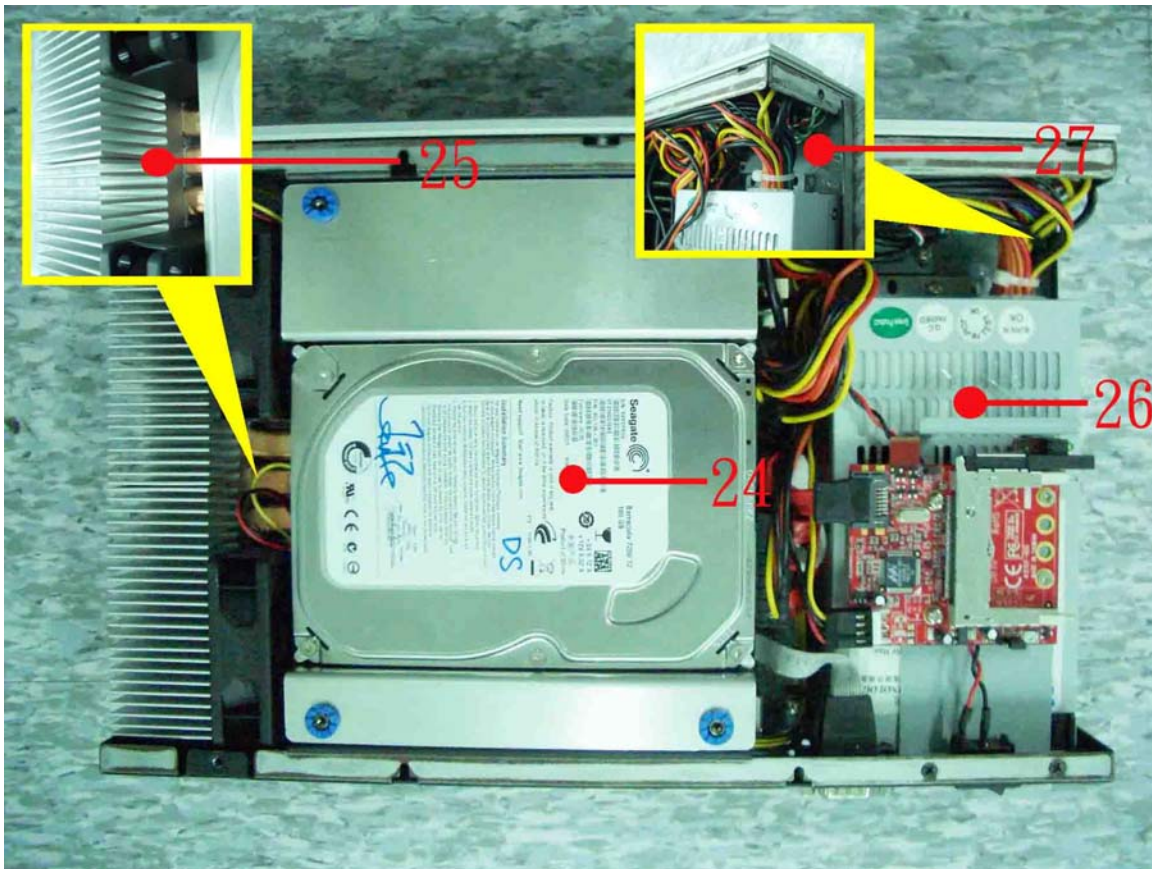
Ambient temperature: 40dC  
Continuous running till thermal stability (within less than 1°C)

**Test Software:**

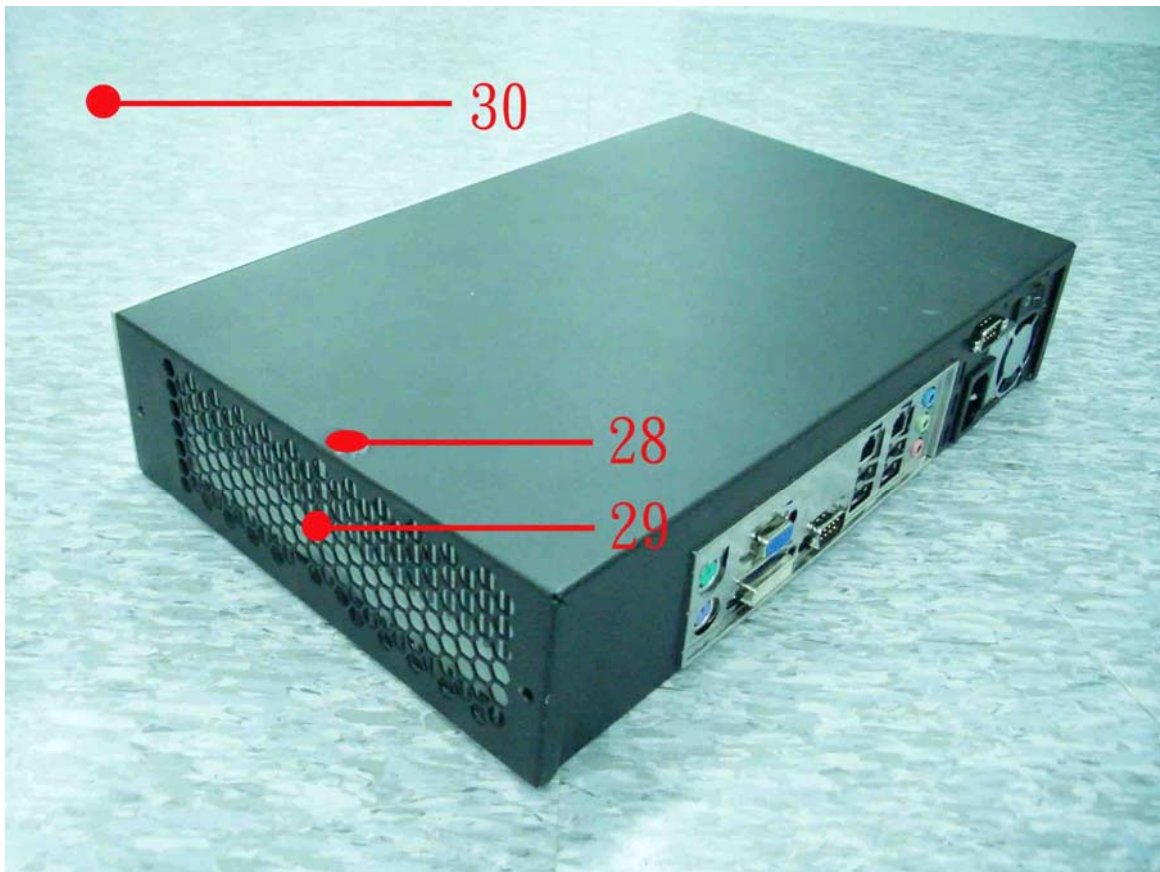
Windows XP / Run PassMark Burn In Test 5.1

**Terminal Recorder:**

Measuring Thermal Couple Position :



# Temperature rise test



# Temperature rise test

## Thermal profile data:

### AIS-Q450

Point	Temp. Stage(°C)	Spec	40	25
01. CPU		71.4	63.9	48.9
02. U13 - (TF) Chipset Intel.AC82Q45 SLB8A		105	63.9	48.9
03. U12 - (TF) Chipset ICH10DO.INTEL.AF82801JDO SLG8U		105	63.6	48.6
04. L6 - (TF) COIL.GOTREND.GSTC135P-2R2MF		125	56.5	41.5
05. Q4 - (TF) PWR.N-channel Power MOSFET.FAIRCHILD.FDD8880		125	59.4	44.4
06. Q8 - (TF) PWR.N-channel Power MOSFET.FAIRCHILD.FDD8896_NL		125	59.7	44.7
07. U5 - (TF) Digital Video Level Shifter.for DP to HDMI.PERICOM.PI3VDP411LSTZDE		85	61.7	46.7
08. U6 - (TF) RS-232 Driver&Receivers.TI.GD75232DBR		95	60.3	45.3
09. U9 - (TF) GigaBit Ethernet Chipset.INTEL.WG82567LM SLAVV		115	66.4	51.4
10. U14 - (TF) PCI-E GigaBit Ethernet Chipset.Intel.WG82574L SLBA8		109	58.5	43.5
11. U15 - (TF)7.1Channel HD Audio Codec.REALTEK.ALC888-VC2-GR		100	58.7	43.7
12.U16 - (TF) Differential Channel /Demux for PCI-E.PERICOM.PI3PCIE2612-AZFE		85	67.9	52.9
13. U27 - (TF) Super I/O.ITE.IT8718F/HX-L		100	62.8	47.8
14. U28 - (TF) 32 Mbit SPI Flash.Winbond.W25X32VSSIG		105	60.1	45.1
15. U29 - (TF) CLOCK GENERATOR.SILEGO.SLG505YC264BTTR		100	60.7	45.7
16. U18 - (TF) MosFET Driver.Intersil.ISL6614ACBZ		100	67.9	52.9
17. U23 - (TF) VR11.1 4Phase PWM Controler.Intersil.ISL6334CRZ		100	79.3	64.3
18. U35 - (TF) REG.Linear Regulator.Diodes.AP1084DG-13		100	63.6	48.6
19. Q81 - (TF) PWR .N-Channel PowerMosfet.ANPEC.APM3054NUC-TR-L		125	59.4	44.4
20. U30 - (TF) OP AMP.NS.LM358M-NOPB		100	60.6	45.6
21. U19 - (TF) MOSFET Drivers.INTERASIL.ISL6612ACBZ		100	63.7	48.7
22. Memory - 1		85	75.9	60.9
23. Memory - 2		85	55.6	40.6
24. HDD		60	48.2	33.2
25. Control Box Inside Air Temperature - 1		N/A	55.4	40.4
26. Control Box Inside Air Temperature - 2		N/A	43.2	28.2
27. Control Box Inside Air Temperature - 3		N/A	43.4	28.4
28. Control Box External Surface - 1		N/A	48.2	33.2
29. Control Box External Surface - 2		N/A	54.3	39.3
30. Chamber Air Temperature		N/A	39.6	24.6
<b>Any Tm value showed in red words which meaning the value over the Tc degree C of this device specification.</b>				

## Sample Configuration & Quantity Under Test:

Quantity: 1 (AIS-Q450)

## Test Result:

No problem was found during the temperature rise operation test.

# Temperature cycle test

**Test Date:** 07-31-2009 ~ 08~03-2009

**Test Product:** AIS-Q450

**Test Site:** AAEON QA Internal Lab.

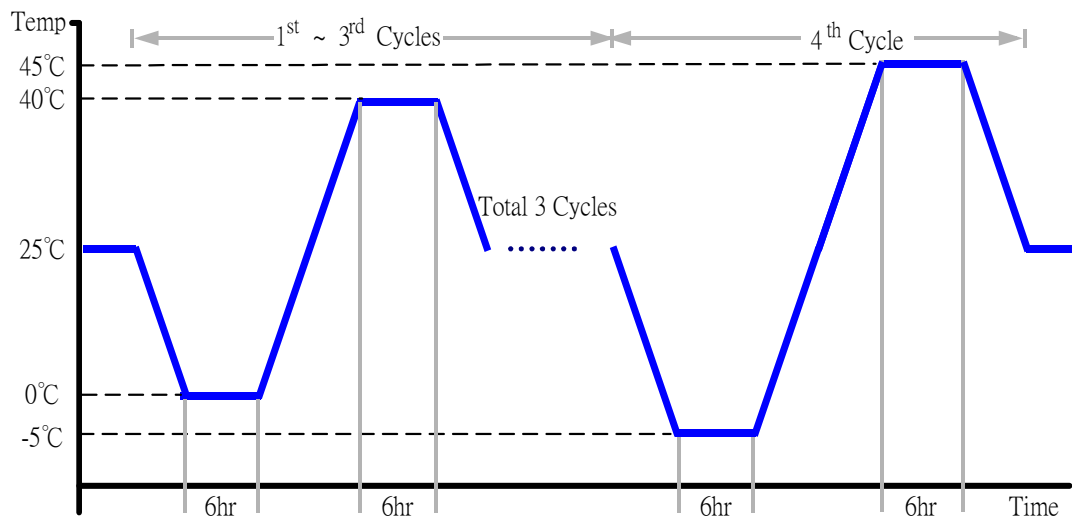
**Test Standard:** Reference IEC68-2-14 Testing procedures  
Test N: Change of temperature Test

**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D4L+-100  
Date of Calibration: 05/07/09  
Serial Number: 1241

**Test Condition:**

1. Test Low Temperature: 0°C (1~3 cycles)  
-5°C (4<sup>th</sup> cycle)
2. Test High Temperature: 40°C (1~3 cycles)  
45°C (4<sup>th</sup> cycle)
3. Test dwell time: 6Hrs
4. Temperature slope: 2°C/min
5. Test cycle: 4 cycles
6. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (AIS-Q450)

**Test Result:**

No problem was found during the temperature operation cycle test.

**Test Date:** 07-29~31-2009

**Test Product:** AIS-Q450

**Test Site:** AAEON QA Internal Lab.

**Test Standard:** Reference IEC 68-2-2 Testing procedures  
Test Bb: Dry Heat Test (Non-operation)

**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.

Model: THS-D4L+-100

Date of Calibration: 05/07/09

Serial Number: 1241

**Testing Item:**

1. Test Temperature: 60°C
2. Test Times: 48Hrs
3. Test Software: Windows XP / Run PassMark Burn In Test 5.1 Pro
4. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (AIS-Q450)

**Test Result:**

No problem was found after the high temperature storage test.

**Test Date:** 07-27~29-2009

**Test Product:** AIS-Q450

**Test Site:** AAEON QA Internal Lab.

**Test Standard:** Reference IEC 68-2-1 Testing procedures  
Test Ab: Cold Test (Non-operation)

**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.

Model: THS-D4L+-100

Date of Calibration: 05/07/09

Serial Number: 1241

**Testing Item:**

1. Test Temperature: -20°C
2. Test Times: 48Hrs
3. Test Software: Windows XP / Run PassMark Burn In Test 5.1 Pro
4. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**  
Quantity: 1 (AIS-Q450)

**Test Result:**

No problem was found after the low temperature storage test.



**Test Date:** 07-24~27-2009

**Test Product:** AIS-Q450

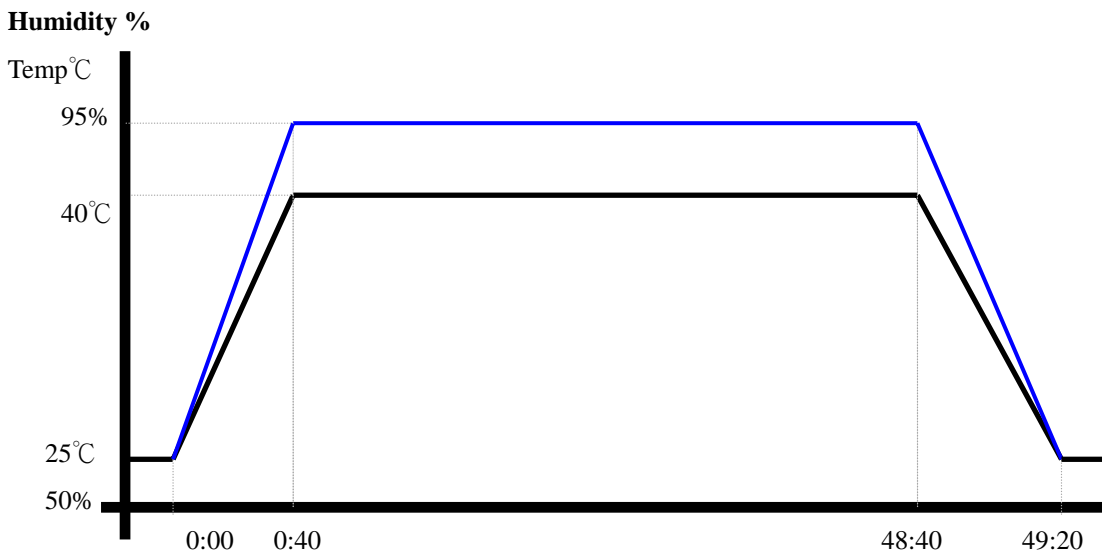
**Test Site:** AAEON QA Internal Lab.

**Test Standard:** Reference IEC 68-2-3 Testing procedures  
Test Ca: Damp heat, steady state (Non-operation)

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D4L+-100  
Date of Calibration: 05/07/09  
Serial Number: 1241

**Testing Item:**

1. Test Temperature: 40°C
2. Test Humidity: 95%RH
3. Test Times: 48Hrs
4. Test Software: Windows XP / Run PassMark Burn In Test 5.1 Pro
5. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**  
Quantity: 1 (AIS-Q450)

**Test Result:**  
No problem was found after the humidity storage test.

# Cold start and hot start test

**Test Date:** 08-03~04-2009

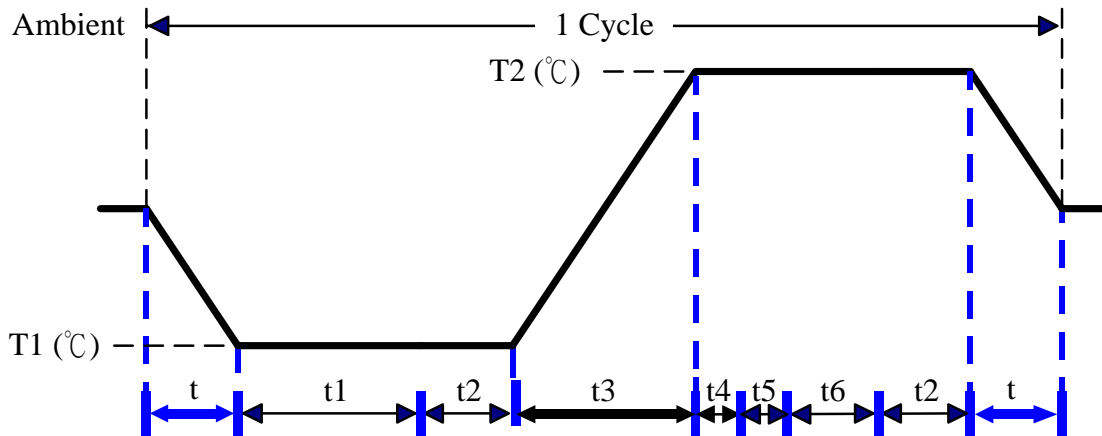
**Test Product:** AIS-Q450

**Test Site:** AAEON QA Internal Lab.

**Test Standard:** Reference IEC 68-2-14 Testing procedures  
Test N: Change of temperature Test

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D4L+-100  
Date of Calibration: 05/07/09  
Serial Number: 1241

**Test Condition:**



Parameters	Description
T1	-5°C
T2	45°C
t1	4 hrs
t2, t6	2 hrs
t4, t5	1 hrs
t, t3	2°C/min
n (Cycle)	1

t = temperature slope  
t, t1, t6: Power Off  
t2: Power on/off test 10 times (on 2 min / off 5min)  
t3, t4: Run PassMark Burn In Test  
t5: Win XP Software restart test 3 times  
Test Software: Windows XP

**Test Result:**

- a. No problem was found during the cold start test.
- b. No problem was found during the hot start test.